

September 1992 Revised November 1999

74ABT2541

Octal Buffer/Line Driver with 25 Ω Series Resistors in the Outputs

General Description

The ABT2541 is an octal buffer and line driver designed to drive the capacitive inputs of MOS memory drivers, address drivers, clock drivers, and bus-oriented transmitters/receivers. Functionally identical to the ABT541.

The 25Ω series resistors in the outputs reduce ringing and eliminate the need for external resistors.

Features

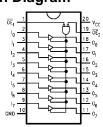
- Guaranteed output skew
- Guaranteed multiple output switching specifications
- Output switching specified for both 50 pF and 250 pF loads
- Guaranteed simultaneously switching noise level and dynamic threshold performance
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability
- Disable time less than enable time to avoid bus contention

Ordering Code:

Order Number	Package Number	Package Description
74ABT2541CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ABT2541CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT2541CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74ABT2541CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Devices also available in Tape and Reel. Specify by appending "X" to the ordering code.

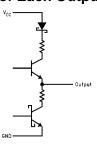
Connection Diagram



Pin Descriptions

Pin Names	Description
$\overline{OE}_1, \overline{OE}_2$	Output Enable Input (Active LOW)
I ₀ -I ₇	Inputs
O ₀ -O ₇	Outputs

Schematic of Each Output



Truth Table

	Inputs	Outmute	
OE ₁	OE ₂	I	Outputs
L	L	Н	Н
Н	X	X	Z
Х	Н	Х	Z
L	L	L	L

- H = HIGH Voltage Level
- L = LOW Voltage Level X = Immaterial
- Z = High Impedance

Absolute Maximum Ratings(Note 1)

 $\begin{array}{ll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to } +125^{\circ}\mbox{C} \\ \end{array}$

 $\begin{array}{lll} \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{V}_{\mbox{CC}} \mbox{ Pin Potential to Ground Pin} & -0.5\mbox{V to } +7.0\mbox{V} \end{array}$

Input Voltage (Note 2) -0.5V to +7.0V Input Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Any Output

in the Disabled or

Power-Off State -0.5V to 5.5V in the HIGH State -0.5V to V_{CC}

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA) DC Latchup Source Current -500 mA

Over Voltage Latchup (I/O) 10V

Recommended Operating Conditions

Free Air Ambient Temperature -40°C to +85°C Supply Voltage +4.5V to +5.5V

Minimum Input Edge Rate ($\Delta V/\Delta t$)

Data Input 50 mV/ns
Enable Input 20 mV/ns

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parame	eter	Min	Тур	Max	Units	v _{cc}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized LOW Signal
V _{CD}	Input Clamp Diode Vol	tage			-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	H Output HIGH Voltage		2.5			V	Min	$I_{OH} = -3 \text{ mA}$
			2.0			V	Min	$I_{OH} = -32 \text{ mA}$
V _{OL}	Output LOW Voltage				8.0	V	Min	I _{OL} = 15 mA
I _{IH}	Input HIGH Current				1	μΑ	Max	V _{IN} = 2.7V (Note 3)
					1			$V_{IN} = V_{CC}$
I _{BVI}	Input HIGH Current				7	μА	Max	V _{IN} = 7.0V
	Breakdown Test				,	μΛ	IVIAX	V _{IN} = 7.0 V
I _{IL}	Input LOW Current				-1	μА	Max	V _{IN} = 0.5V (Note 3)
					-1	μΛ	IVIAX	$V_{IN} = 0.0V$
V _{ID}	Input Leakage Test		4.75			V	0.0	$I_{ID} = 1.9 \mu\text{A}$
								All Other Pins Grounded
I _{OZH}	Output Leakage Curre	nt			10	μΑ	0 – 5.5V	$V_{OUT} = 2.7V; \overline{OE}_n = 2.0V$
I _{OZL}	Output Leakage Curre	nt			-10	μΑ	0 – 5.5V	$V_{OUT} = 0.5V; \overline{OE}_n = 2.0V$
Ios	Output Short-Circuit C	urrent	-100		-275	mA	Max	V _{OUT} = 0.0V
I _{CEX}	Output High Leakage	Current			50	μΑ	Max	V _{OUT} = V _{CC}
I _{ZZ}	Bus Drainage Test				100	μΑ	0.0	V _{OUT} = 5.5V; All Others GND
I _{CCH}	Power Supply Current				50	μΑ	Max	All Outputs HIGH
I _{CCL}	Power Supply Current				30	mA	Max	All Outputs LOW
I _{CCZ}	Power Supply Current				50	μΑ	Max	$\overline{OE}_n = V_{CC};$
								All Others at V _{CC} or GND
I _{CCT}	Additional I _{CC} /Input	Outputs Enabled			2.5	mA		$V_I = V_{CC} - 2.1V$
		Outputs 3-STATE			2.5	mA	Max	Enable Input $V_I = V_{CC} - 2.1V$
		Outputs 3-STATE			50	μΑ		Data Input $V_I = V_{CC} - 2.1V$
								All Others at V _{CC} or GND
I _{CCD}	Dynamic I _{CC}	No Load				mA/	May	Outputs OPEN
	(Note 4)				0.1	MHz	Max	$\overline{OE}_n = GND$ (Note 3)
								One Bit Toggling, 50% Duty Cycle
l	<u> </u>						l .	

Note 3: Guaranteed, but not tested.

Note 4: For 8 bit toggling, $I_{\mbox{\scriptsize CCD}} < 0.8$ mA/MHz.

DC Electrical Characteristics

(SOIC Package)

Symbol	Parameter	Min	Тур	Max	Units	v _{cc}	Conditions $\mathbf{C_L} = 50 \ \mathbf{pF}, \ \mathbf{R_L} = 500 \Omega$
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}		0.6	8.0	V	5.0	T _A = 25°C (Note 5)
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	-0.5	-0.4		V	5.0	T _A = 25°C (Note 5)
V _{OHV}	Minimum HIGH Level Dynamic Output Voltage	2.7	3.1		V	5.0	T _A = 25°C (Note 6)
V_{IHD}	Minimum HIGH Level Dynamic Input Voltage	2.0	1.4		V	5.0	T _A = 25°C (Note 7)
V_{ILD}	Maximum LOW Level Dynamic Input Voltage		1.2	0.8	V	5.0	T _A = 25°C (Note 7)

Note 5: Max number of outputs defined as (n). n-1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.

Note 6: Max number of data inputs (n) switching. n-1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}). Guaranteed, but not tested.

Note 7: Max number of outputs defined as (n). n - 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

AC Electrical Characteristics

Symbol	Parameter	$T_{A} = +25^{\circ}$ $V_{CC} = +5$ $C_{L} = 50 \ p$			$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V} - 5.5\text{V}$ $C_L = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	
t _{PLH}	Propagation Delay Data to Outputs	1.0	2.3	3.6	1.0	3.6	20
t _{PHL}		1.0	3.3	4.1	1.0	4.1	ns
t _{PZH}	Output Enable Time	1.5	3.7	6.0	1.5	6.0	20
t_{PZL}		1.5	4.3	6.5	1.5	6.5	ns
t _{PHZ}	Output Disable Time	1.0	3.5	6.0	1.0	6.0	ns
t_{PLZ}		1.0	3.7	5.6	1.0	5.6	115

Extended AC Electrical Characteristics

(SOIC Package)

Symbol Parameter		-40° C to +85°C $V_{CC} = 4.5V-5.5V$ $C_{L} = 50 \text{ pF}$ 8 Outputs Switching (Note 8)		$T_A = -40$ °C to +85°C $V_{CC} = 4.5V-5.5V$ $C_L = 250$ pF 1 Output Switching (Note 9)		$T_A = -40^{\circ}\text{C to} +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V}-5.5\text{V}$ $C_L = 250 \text{ pF}$ 8 Outputs Switching (Note 10)		Units	
		Min	Тур	Max	Min	Max	Min	Max	
f _{TOGGLE}	Maximum Toggle Frequency		100						MHz
t _{PLH}	Propagation Delay	1.5		5.0	1.5	6.0	2.5	8.5	ns
t _{PHL}	Data to Outputs	1.5		5.5	1.5	10.0	2.5	11.0	115
t _{PZH}	Output Enable Time	1.5		6.5	2.5	7.5	2.5	9.5	ns
t_{PZL}		1.5		7.0	2.5	11.0	2.5	12.5	115
t _{PHZ}	Output Disable Time	1.0		6.0	(Not	e 11)	(Not	e 11)	ns
t _{PLZ}		1.0		6.0	(1401)	5 11)	(1401	6 11)	113

Note 8: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Note 9: This specification is guaranteed but not tested. The limits represent propagation delay with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

Note 10: This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 11: The 3-STATE delays are dominated by the RC network (500 Ω , 250 pF) on the output and have been excluded from the datasheet.

Skew

(SOIC Package)

Symbol	Parameter	$T_A = -40$ °C to +85 °C $V_{CC} = 4.5V - 5.5V$ $C_L = 50$ pF 8 Outputs Switching (Note 12)	$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V} - 5.5\text{V}$ $C_L = 250 \text{ pF}$ 8 Outputs Switching (Note 13)	Units
toshl	Pin to Pin Skew	1.3	2.3	ns
(Note 14)	HL Transitions	-	-	-
t _{OSLH}	Pin to Pin Skew	1.0	1.8	ns
(Note 14)	LH Transitions	1.0	1.0	
t _{PS}	Duty Cycle	2.0	5.0	ns
(Note 15)	LH-HL Skew	2.0	5.0	115
tost	Pin to Pin Skew	2.0	5.0	ns
(Note 14)	LH/HL Transitions	2.0	5.0	115
t _{PV}	Device to Device Skew	2.0	5.0	ns
(Note 16)	LH/HL Transitions	2.0	5.0	115

Note 12: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.)

Note 13: These specifications guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 14: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW (t_{OSHL}), LOW-to-HIGH (t_{OSLH}), or any combination switching LOW-to-HIGH and/or HIGH-to-LOW (t_{OST}). The specification is guaranteed but not tested.

Note 15: This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested.

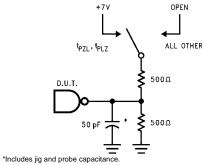
Note 16: Propagation delay variation for a given set of conditions (i.e., temperature and V_{CC}) from device to device. This specification is guaranteed but not tested

Capacitance

Symbol	Parameter	Тур	Units	Conditions T _A = 25°C
C _{IN}	Input Capacitance	5.0	pF	V _{CC} = 0V
C _{OUT} (Note 17)	Output Capacitance	9.0	pF	V _{CC} = 5.0V

Note 17: C_{OUT} is measured at frequency f = 1 MHz; per MIL-STD-883, Method 3012.

AC Loading



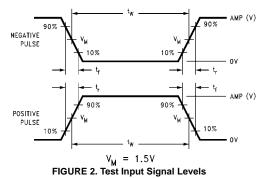


FIGURE 1. Standard AC Test Load

Amplitude	Rep. Rate	t _W	t _r	t _f
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

FIGURE 3. Test Input Signal Requirements

AC Waveforms

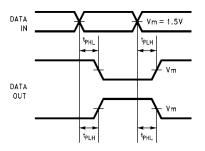


FIGURE 4. Propagation Delay Waveforms for **Inverting and Non-Inverting Functions**

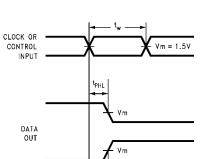


FIGURE 5. Propagation Delay, Pulse Width Waveforms

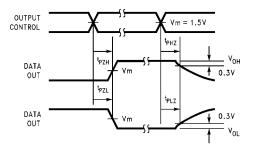


FIGURE 6. 3-STATE Output HIGH and LOW Enable and Disable Times

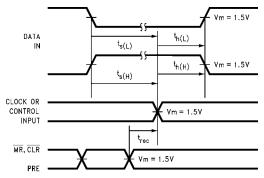
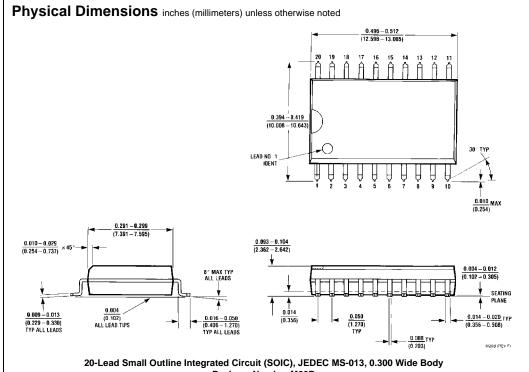
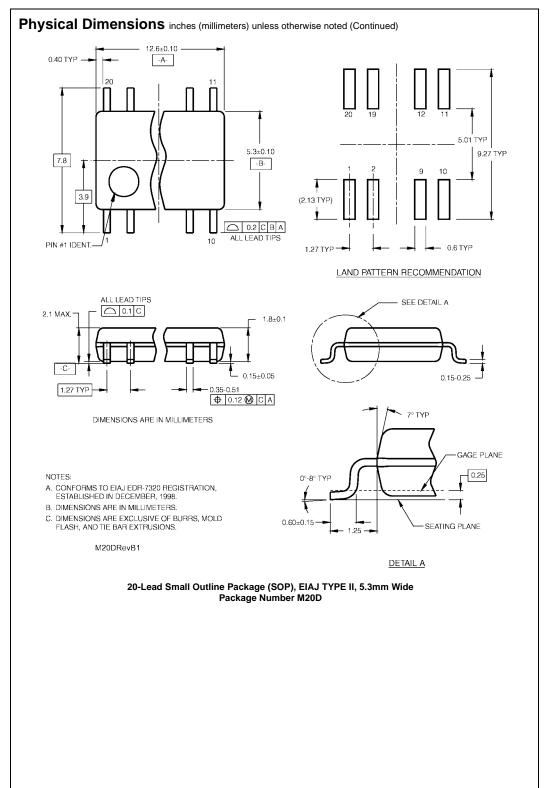
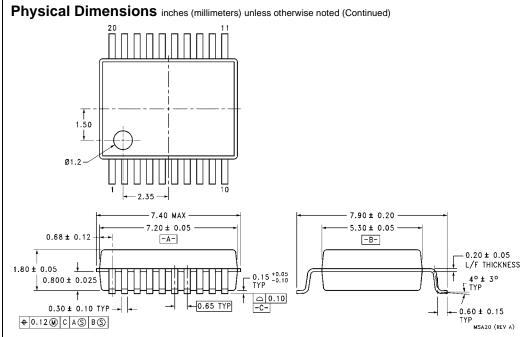


FIGURE 7. Setup Time, Hold Time and Recovery Time Waveforms

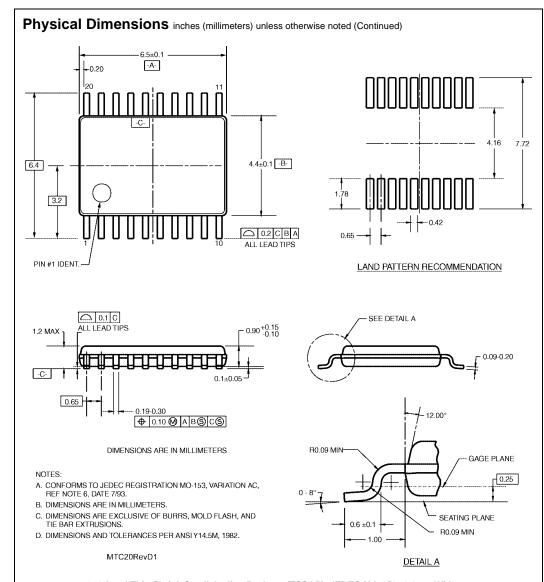


20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide Body Package Number M20B





20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide Package Number MSA20



20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC20

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